

Atmos. Meas. Tech. Discuss., 5, C4014–C4015, 2013

www.atmos-meas-tech-discuss.net/5/C4014/2013/

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AMTD

5, C4014–C4015, 2013

Interactive
Comment

Interactive comment on “Biases caused by the instrument bandwidth and beam width on simulated brightness temperature measurements from scanning microwave radiometers” by V. Meunier et al.

V. Meunier et al.

veronique.meunier2@mail.mcgill.ca

Received and published: 25 February 2013

Dear Reviewer,

The response to your comments and concerns is found in the attached PDF file.

Cheers, Veronique Meunier

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Interactive Discussion

Discussion Paper



Please also note the supplement to this comment:
<http://www.atmos-meas-tech-discuss.net/5/C4014/2013/amtd-5-C4014-2013-supplement.pdf>

Interactive comment on Atmos. Meas. Tech. Discuss., 5, 8085, 2012.

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C4015

